

PALM INTRANET

Day : Monday  
 Date: 10/15/2007  
 Time: 11:13:04

**Inventor Name Search Result**

Your Search was:

Last Name = TAI

First Name = HUNG-EN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<a href="#">10249147</a>	Not Issued	30	03/19/2003	METHOD OF MANAGING SEMICONDUCTOR MANUFACTURING CASES	TAI, HUNG-EN
<a href="#">10249148</a>	<a href="#">7079677</a>	150	03/19/2003	AN AUTOMATIC INTELLIGENT YIELD IMPROVING AND PROCESS PARAMETER MULTIVARIATE SYSTEM AND THE ANAYSIS METHOD THEREOF	TAI, HUNG-EN
<a href="#">10249213</a>	<a href="#">6968280</a>	150	03/24/2003	METHOD FOR ANALYZING WAFER TEST PARAMETERS	TAI, HUNG-EN
<a href="#">10249375</a>	<a href="#">6904384</a>	150	04/03/2003	COMPLEX MULTIVARIATE ANALYSIS SYSTEM AND METHOD	TAI, HUNG-EN
<a href="#">10604244</a>	<a href="#">6959252</a>	150	07/03/2003	METHOD FOR ANALYZING IN-LINE QC TEST PARAMETERS	TAI, HUNG-EN
<a href="#">10604685</a>	<a href="#">6828776</a>	150	08/11/2003	METHOD FOR ANALYZING DEFECT INSPECTION PARAMETERS	TAI, HUNG-EN
<a href="#">10604979</a>	<a href="#">6898539</a>	150	08/29/2003	METHOD FOR ANALYZING FINAL TEST PARAMETERS	TAI, HUNG-EN
<a href="#">10708277</a>	<a href="#">7099729</a>	150	02/20/2004	SEMICONDUCTOR PROCESS AND YIELD ANALYSIS INTEGRATED REAL-TIME MANAGEMENT METHOD	TAI, HUNG-EN
<a href="#">10708572</a>	<a href="#">6950783</a>	150	03/11/2004	METHOD AND RELATED SYSTEM FOR SEMICONDUCTOR EQUIPMENT PREVENTION MAINTENANCE MANAGEMENT	TAI, HUNG-EN
<a href="#">10708573</a>	<a href="#">6999897</a>	150	03/11/2004	METHOD AND RELATED SYSTEM FOR SEMICONDUCTOR EQUIPMENT EARLY WARNING MANAGEMENT	TAI, HUNG-EN
<a href="#">10711179</a>	Not Issued	30	08/30/2004	DATA ANALYZING METHOD FOR A FAULT DETECTION AND CLASSIFICATION SYSTEM	TAI, HUNG-EN
<a href="#">10711310</a>	Not	30	09/09/2004	Method of Managing Wafer Defects	TAI, HUNG-EN

	Issued				
<u>11401900</u>	<u>7218981</u>	150	04/12/2006	DISPATCH INTEGRATION SYSTEM AND METHOD BASED ON SEMICONDUCTOR MANUFACTURING	TAI, HUNG-EN

Inventor Search Completed: No Records to Display.


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**Search Another: Inventor**

Last Name	First Name	
<input type="text" value="TAI"/>	<input type="text" value="HUNG-EN"/>	<input type="button" value="Search"/>

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Day : Monday  
Date: 10/15/2007  
Time: 11:13:46**Inventor Name Search Result**

Your Search was:

Last Name = CHEN

First Name = CHIA-YUN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<a href="#">10711310</a>	Not Issued	30	09/09/2004	Method of Managing Wafer Defects	CHEN, CHIA-YUN
<a href="#">10904873</a>	Not Issued	41	12/01/2004	METHOD OF DEFECT INSPECTION	CHEN, CHIA-YUN
<a href="#">11213931</a>	<a href="#">7132354</a>	150	08/30/2005	INSPECTION METHODS FOR A SEMICONDUCTOR DEVICE	CHEN, CHIA-YUN
<a href="#">11892759</a>	Not Issued	17	08/27/2007	Man-made material presenting magnetic response at different frequencies	CHEN, CHIA-YUN
<a href="#">11653458</a>	Not Issued	25	01/16/2007	Lower mold assembly for punching a sheet	CHEN, CHIA-YUNG
<a href="#">11540953</a>	Not Issued	41	10/02/2006	Three-dimensional combining structure for an auxiliary lens set	CHENG, CHIA-YUNG

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Inventor Search Completed: No Records to Display.

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**Search Another: Inventor**

<b>Last Name</b>	<b>First Name</b>	
<input type="text" value="CHEN"/>	<input type="text" value="CHIA-YUN"/>	<input type="button" value="Search"/>

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Day : Monday  
 Date: 10/15/2007  
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**Inventor Name Search Result**

Your Search was:

Last Name = WANG

First Name = SHENG-JEN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<a href="#">09940852</a>	<a href="#">6531776</a>	150	08/29/2001	SEMICONDUCTOR DEVICE HAVING REDUCED INTERCONNECT-LINE PARASITIC CAPACITANCE	WANG, SHENG-JEN
<a href="#">10249103</a>	<a href="#">6807454</a>	150	03/17/2003	METHOD FOR AUTOMATICALLY CONTROLLING DEFECT - SPECIFICATION IN A SEMICONDUCTOR MANUFACTURING PROCESS	WANG, SHENG-JEN
<a href="#">10249147</a>	Not Issued	30	03/19/2003	METHOD OF MANAGING SEMICONDUCTOR MANUFACTURING CASES	WANG, SHENG-JEN
<a href="#">10249148</a>	<a href="#">7079677</a>	150	03/19/2003	AN AUTOMATIC INTELLIGENT YIELD IMPROVING AND PROCESS PARAMETER MULTIVARIATE SYSTEM AND THE ANALYSIS METHOD THEREOF	WANG, SHENG-JEN
<a href="#">10708277</a>	<a href="#">7099729</a>	150	02/20/2004	SEMICONDUCTOR PROCESS AND YIELD ANALYSIS INTEGRATED REAL-TIME MANAGEMENT METHOD	WANG, SHENG-JEN
<a href="#">10708572</a>	<a href="#">6950783</a>	150	03/11/2004	METHOD AND RELATED SYSTEM FOR SEMICONDUCTOR EQUIPMENT PREVENTION MAINTENANCE MANAGEMENT	WANG, SHENG-JEN
<a href="#">10708573</a>	<a href="#">6999897</a>	150	03/11/2004	METHOD AND RELATED SYSTEM FOR SEMICONDUCTOR EQUIPMENT EARLY WARNING MANAGEMENT	WANG, SHENG-JEN
<a href="#">10711310</a>	Not Issued	30	09/09/2004	Method of Managing Wafer Defects	WANG, SHENG-JEN
<a href="#">11228361</a>	<a href="#">7260444</a>	150	09/19/2005	REAL-TIME MANAGEMENT SYSTEMS AND METHODS FOR MANUFACTURING MANAGEMENT AND YIELD RATE ANALYSIS INTEGRATION	WANG, SHENG-JEN

## Inventor Search Completed: No Records to Display.

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	WANG	SHENG-JEN	

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1	BRS	1	inspect\$3 and (wafer\$1 or semicondutor\$1 or chip\$1 or substrat\$1 or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring adj board)and generat\$3 adj defect\$3 and raw adj data and server adj integrat\$3 and wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
2	BRS	0	S3 and server adj integrate with wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
3	BRS	0	S3 and (pre adj treatment or pre-treatment)and server and integrate and wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
4	BRS	0	S3 and server and integrate and wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
5	BRS	25	inspect\$3 and (wafer\$1 or semicondutor\$1 or chip\$1 or substrat\$1 or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring adj board)and generat\$3 adj defect\$3 and raw adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
6	BRS	2	"6763130".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
7	BRS	2	S12 and (@ad<"20040909" or @rlad<"20040909" or @prad<"20040909" or @ptad<"20040909")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
8	BRS	2	S12 and @ad<"20040909"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
9	BRS	3	S2 and server and integrat\$3 and wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
10	BRS	1	S2 and server adj integrat\$3 and wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
11	BRS	0	S3 and server adj integrate and wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Time Stamp	Comments	Error Definition	Errors	Ref #
1	2007/09/06 12:16				S11
2	2007/09/06 12:13				S7
3	2007/09/06 12:12				S6
4	2007/09/06 12:17				S13
5	2007/09/06 11:59				S2
6	2007/09/06 11:51				S1
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9	2007/09/06 12:17				S12
10	2007/09/06 12:14				S10
11	2007/09/06 12:17				S8

	Type	Hits	Search Text	DBs
12	BRS	0	S3 and (pre adj treatment or pre-treatment)and server and integrate same wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
13	BRS	14	S2 and (@ad<"20040909" or @rlad<"20040909" or @prad<"20040909" or @ptad<"20040909")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
14	BRS	0	S3 and server adj integrat\$3 and wafer\$1 adj defect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
15	BRS	2	"7103210".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB



	Time Stamp	Comments	Error Definition	Errors	Ref #
12	2007/09/06 12:12				S5
13	2007/09/06 12:18				S3
14	2007/09/06 12:14				S9
15	2007/09/06 13:56				S16